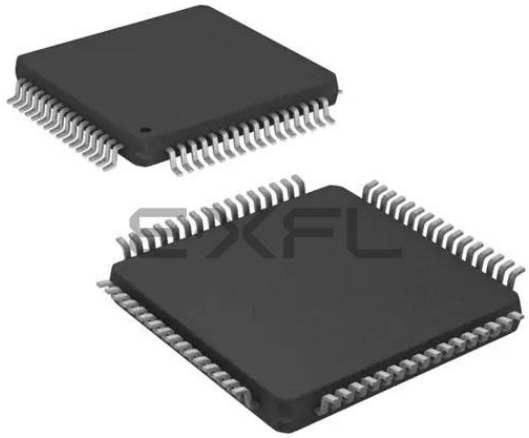

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	AVR
Core Size	8/16-Bit
Speed	32MHz
Connectivity	I²C, IrDA, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	50
Program Memory Size	256KB (128K x 16)
Program Memory Type	FLASH
EEPROM Size	4K x 8
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 3.6V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	64-TQFP
Supplier Device Package	64-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/atxmega256d3-an

19. RTC – 16-bit Real-Time Counter

19.1 Features

- 16-bit resolution
- Selectable clock source
  - 32.768kHz external crystal
  - External clock
  - 32.768kHz internal oscillator
  - 32kHz internal ULP oscillator
- Programmable 10-bit clock prescaling
- One compare register
- One period register
- Clear counter on period overflow
- Optional interrupt/event on overflow and compare match

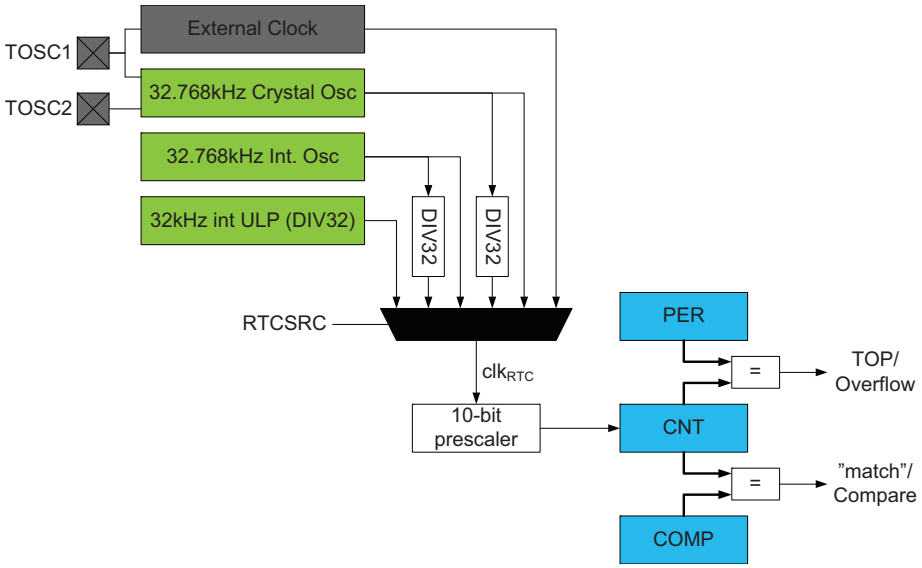
19.2 Overview

The 16-bit real-time counter (RTC) is a counter that typically runs continuously, including in low-power sleep modes, to keep track of time. It can wake up the device from sleep modes and/or interrupt the device at regular intervals.

The reference clock is typically the 1.024kHz output from a high-accuracy crystal of 32.768kHz, and this is the configuration most optimized for low power consumption. The faster 32.768kHz output can be selected if the RTC needs a resolution higher than 1ms. The RTC can also be clocked from an external clock signal, the 32.768kHz internal oscillator or the 32kHz internal ULP oscillator.

The RTC includes a 10-bit programmable prescaler that can scale down the reference clock before it reaches the counter. A wide range of resolutions and time-out periods can be configured. With a 32.768kHz clock source, the maximum resolution is 30.5µs, and time-out periods can range up to 2000 seconds. With a resolution of 1s, the maximum timeout period is more than18 hours (65536 seconds). The RTC can give a compare interrupt and/or event when the counter equals the compare register value, and an overflow interrupt and/or event when it equals the period register value.

Figure 19-1. Real-time Counter Overview



32.1.8 Bandgap and Internal 1.0V Reference Characteristics

Table 32-13. Bandgp and Internal 1.0V Reference Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Startup time	As reference for ADC		1 Clk_{PER} + 2.5µs		µs
		As input voltage to ADC and AC		1.5		
	Bandgap voltage			1.1		V
INT1V	Internal 1.00V reference	T = 85°C, after calibration	0.99	1	1.01	
	Variation over voltage and temperature	Calibrated at T = 85°C		1		%

32.1.9 Brownout Detection Characteristics

Table 32-14. Brownout Detection Characteristics (1)

Symbol	Parameter (BOD level 0 at 85°C)	Condition	Min.	Typ.	Max.	Units
V_{BOT}	BOD level 0 falling V_{CC}		1.40	1.60	1.70	V
	BOD level 1 falling V_{CC}			1.8		
	BOD level 2 falling V_{CC}			2.0		
	BOD level 3 falling V_{CC}			2.2		
	BOD level 4 falling V_{CC}			2.4		
	BOD level 5 falling V_{CC}			2.6		
	BOD level 6 falling V_{CC}			2.8		
	BOD level 7 falling V_{CC}			3.0		
t_{BOD}	Detection time	Continuous mode		0.4		µs
		Sampled mode		1000		
V_{HYST}	Hysteresis			1.0		%

Note: 1. BOD is calibrated at 85°C within BOD level 0 values, and BOD level 0 is the default level.

32.1.10 External Reset Characteristics

Table 32-15. External Reset Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
t_{EXT}	Minimum reset pulse width		1000	90		ns
V_{RST}	Reset threshold voltage	V_{CC} = 2.7 - 3.6V		0.45 * V_{CC}		V
		V_{CC} = 1.6 - 2.7V		0.42 * V_{CC}		
R_{RST}	Reset pin pull-up resistor			25		kΩ

32.2.3 Current Consumption

Table 32-33. Current Consumption for Active Mode and Sleep Modes

Symbol	Parameter	Condition		Min.	Typ.	Max.	Units
I_{CC}	Active power consumption (1)	32kHz, Ext. Clk	V_{CC} = 1.8V		50		µA
			V_{CC} = 3.0V		130		
		1MHz, Ext. Clk	V_{CC} = 1.8V		215		
			V_{CC} = 3.0V		475		
		2MHz, Ext. Clk	V_{CC} = 1.8V		445	600	
			V_{CC} = 3.0V		0.95	1.5	mA
		32MHz, Ext. Clk			7.8	12.0	
	Idle power consumption (1)	32kHz, Ext. Clk	V_{CC} = 1.8V		2.8		µA
			V_{CC} = 3.0V		3		
		1MHz, Ext. Clk	V_{CC} = 1.8V		46		
			V_{CC} = 3.0V		92		
		2MHz, Ext. Clk	V_{CC} = 1.8V		93	225	
			V_{CC} = 3.0V		184	350	
		32MHz, Ext. Clk			2.9	5.0	mA
	Power-down power consumption	T = 25°C	V_{CC} = 3.0V		0.07	1.0	µA
		T = 85°C			1.3	5.0	
		T = 105°C			4.0	8.0	
		WDT and sampled BOD enabled, T = 25°C	V_{CC} = 3.0V		1.3	2.0	
		WDT and sampled BOD enabled, T = 85°C			2.6	6.0	
		WDT and sampled BOD enabled, T= 105°C			5.0	10	
	Power-save power consumption (2)	RTC from ULP clock, WDT and sampled BOD enabled, T = 25°C	V_{CC} = 1.8V		1.7		
			V_{CC} = 3.0V		1.8		
		RTC from 1.024kHz low power 32.768kHz TOSC, T = 25°C	V_{CC} = 1.8V		0.5	2.0	
			V_{CC} = 3.0V		0.7	2.0	
		RTC from low power 32.768kHz TOSC, T = 25°C	V_{CC} = 1.8V		0.9	3.0	
			V_{CC} = 3.0V		1.2	3.0	
	Reset power consumption	Current through $\overline{\text{RESET}}$ pin substracted	V_{CC} = 3.0V		120		

Notes: 1. All Power Reduction Registers set.
2. Maximum limits are based on characterization, and not tested in production.

32.2.8 Bandgap and Internal 1.0V Reference Characteristics

Table 32-42. Bandgap and Internal 1.0V Reference Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Startup time	As reference for ADC		1 Clk_{PER} + 2.5µs		µs
		As input voltage to ADC and AC		1.5		
	Bandgap voltage			1.1		V
INT1V	Internal 1.00V reference	T = 85°C, after calibration	0.99	1	1.01	
	Variation over voltage and temperature	Calibrated at T = 85°C		1		%

32.2.9 Brownout Detection Characteristics

Table 32-43. Brownout Detection Characteristics (1)

Symbol	Parameter (BOD level 0 at 85°C)	Condition	Min.	Typ.	Max.	Units
V_{BOT}	BOD level 0 falling V_{CC}		1.40	1.60	1.70	V
	BOD level 1 falling V_{CC}			1.8		
	BOD level 2 falling V_{CC}			2.0		
	BOD level 3 falling V_{CC}			2.2		
	BOD level 4 falling V_{CC}			2.4		
	BOD level 5 falling V_{CC}			2.6		
	BOD level 6 falling V_{CC}			2.8		
	BOD level 7 falling V_{CC}			3.0		
t_{BOD}	Detection time	Continuous mode		0.4		µs
		Sampled mode		1000		
V_{HYST}	Hysteresis			1.0		%

Note: 1. BOD is calibrated at 85°C within BOD level 0 values, and BOD level 0 is the default level.

32.2.10 External Reset Characteristics

Table 32-44. External Reset Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
t_{EXT}	Minimum reset pulse width		1000	90		ns
V_{RST}	Reset threshold voltage	V_{CC} = 2.7 - 3.6V		0.45 * V_{CC}		V
		V_{CC} = 1.6 - 2.7V		0.42 * V_{CC}		
R_{RST}	Reset pin pull-up resistor			25		kΩ

Table 32-116. Two-wire Interface Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{IH}	Input high voltage		$0.7V_{CC}$		V_{CC} + 0.5	V
V_{IL}	Input low voltage		-0.5		$0.3V_{CC}$	
V_{hys}	Hysteresis of Schmitt trigger inputs		$0.05V_{CC}$ (1)			
V_{OL}	Output low voltage	3mA, sink current	0		0.4	
t_r	Rise time for both SDA and SCL		$20 + 0.1C_b$ (1)(2)		300	ns
t_{of}	Output fall time from V_{IHmin} to V_{ILmax}	$10pF < C_b < 400pF$ (2)	$20 + 0.1C_b$ (1)(2)		250	
t_{SP}	Spikes suppressed by input filter		0		50	
I_I	Input current for each I/O pin	$0.1V_{CC} < V_I < 0.9V_{CC}$	-10		10	µA
C_I	Capacitance for each I/O pin				10	pF
f_{SCL}	SCL clock frequency	f_{PER} (3) > max($10f_{SCL}$, 250kHz)	0		400	kHz
R_P	Value of pull-up resistor	$f_{SCL} \leq 100kHz$	$\frac{V_{CC}-0.4V}{3mA}$		$\frac{100ns}{C_b}$	Ω
		$f_{SCL} > 100kHz$			$\frac{300ns}{C_b}$	
$t_{HD;STA}$	Hold time (repeated) START condition	$f_{SCL} \leq 100kHz$	4.0			µs
		$f_{SCL} > 100kHz$	0.6			
t_{LOW}	Low period of SCL clock	$f_{SCL} \leq 100kHz$	4.7			
		$f_{SCL} > 100kHz$	1.3			
t_{HIGH}	High period of SCL clock	$f_{SCL} \leq 100kHz$	4.0			
		$f_{SCL} > 100kHz$	0.6			
$t_{SU;STA}$	Set-up time for a repeated START condition	$f_{SCL} \leq 100kHz$	4.7			
		$f_{SCL} > 100kHz$	0.6			
$t_{HD;DAT}$	Data hold time	$f_{SCL} \leq 100kHz$	0		3.45	µs
		$f_{SCL} > 100kHz$	0		0.9	
$t_{SU;DAT}$	Data setup time	$f_{SCL} \leq 100kHz$	250			
		$f_{SCL} > 100kHz$	100			
$t_{SU;STO}$	Setup time for STOP condition	$f_{SCL} \leq 100kHz$	4.0			
		$f_{SCL} > 100kHz$	0.6			
t_{BUF}	Bus free time between a STOP and START condition	$f_{SCL} \leq 100kHz$	4.7			
		$f_{SCL} > 100kHz$	1.3			

Notes:
1. Required only for $f_{SCL} > 100kHz$.
2. C_b = Capacitance of one bus line in pF.
3. f_{PER} = Peripheral clock frequency.

32.5.13 Clock and Oscillator Characteristics

32.5.13.1 Calibrated 32.768kHz Internal Oscillator Characteristics

Table 32-135. 32.768kHz Internal Oscillator Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Frequency			32.768		kHz
	Factory calibration accuracy	T = 85°C, V_{CC} = 3.0V	-0.5		0.5	%
	User calibration accuracy		-0.5		0.5	

32.5.13.2 Calibrated 2MHz RC Internal Oscillator Characteristics

Table 32-136. 2MHz Internal Oscillator Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Frequency range	DFLL can tune to this frequency over voltage and temperature	1.8	2.0	2.2	MHz
	Factory calibrated frequency			2.0		
	Factory calibration accuracy	T = 85°C, V_{CC} = 3.0V	-1.5		1.5	%
	User calibration accuracy		-0.2		0.2	
	DFLL calibration stepsize			0.18		

32.5.13.3 Calibrated 32MHz Internal Oscillator Characteristics

Table 32-137. 32MHz Internal Oscillator Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Frequency range	DFLL can tune to this frequency over voltage and temperature	30	32	55	MHz
	Factory calibrated frequency			32		
	Factory calibration accuracy	T = 85°C, V_{CC} = 3.0V	-1.5		1.5	%
	User calibration accuracy		-0.2		0.2	
	DFLL calibration step size			0.19		

32.5.13.4 32kHz Internal ULP Oscillator Characteristics

Table 32-138. 32kHz Internal ULP Oscillator Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Factory calibrated frequency			32		kHz
	Factory calibration accuracy	T = 85°C, V_{CC} = 3.0V	-12		12	%

32.6.14 SPI Characteristics

Figure 32-40. SPI Timing Requirements in Master Mode

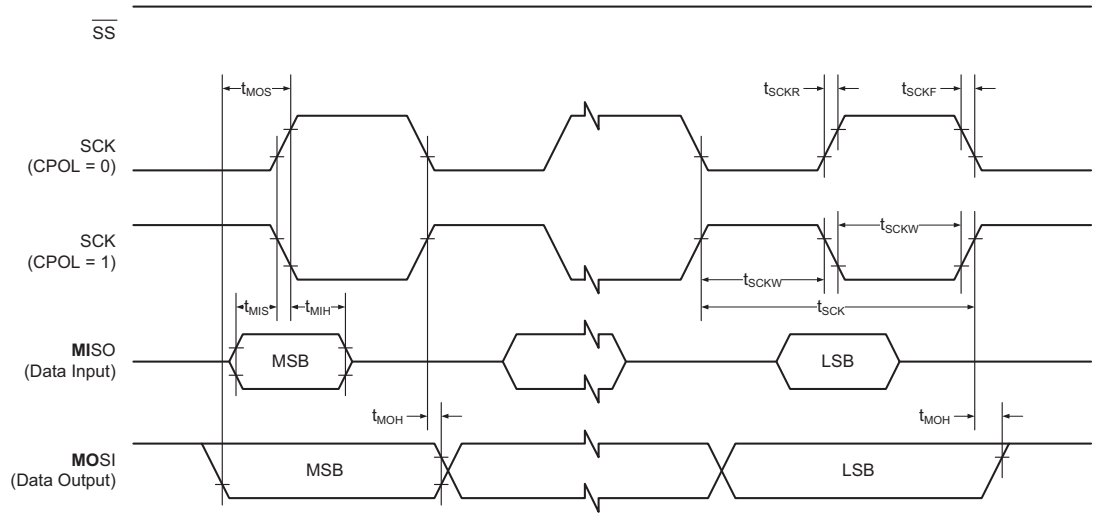


Figure 32-41.SPI Timing Requirements in Slave Mode

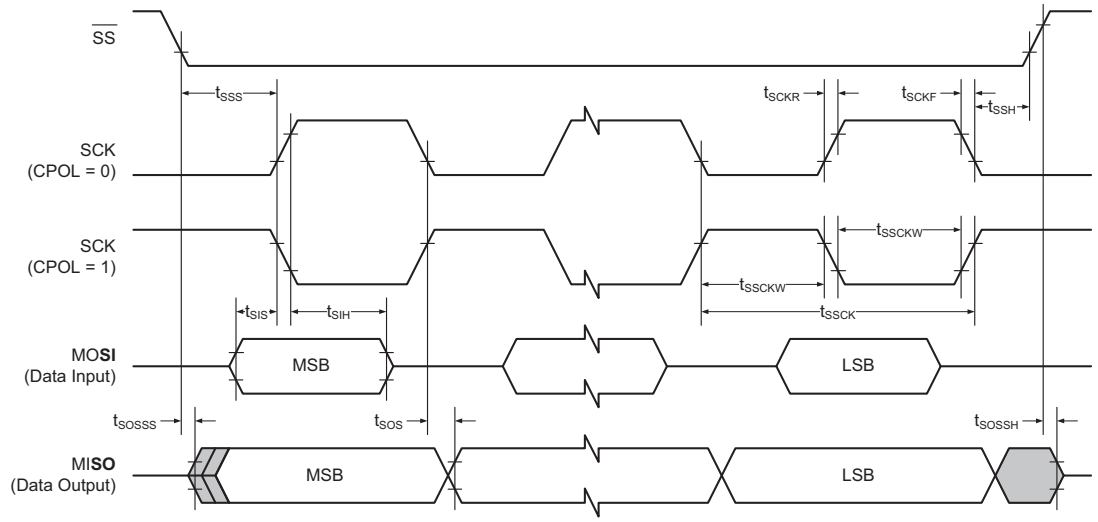


Figure 33-37. Gain Error vs. V_{REF}

T = 25°C, V_{CC} = 3.6V, ADC sample rate = 300ksps

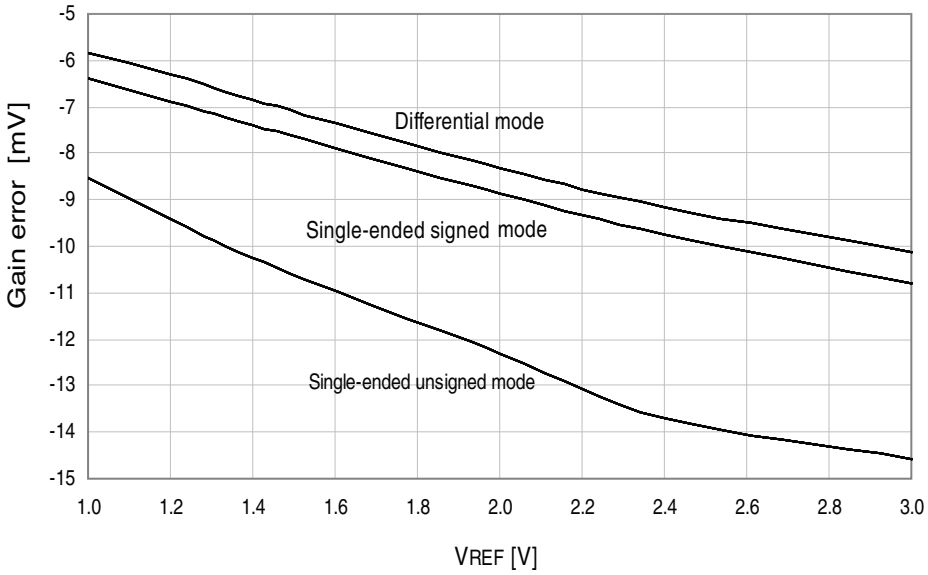


Figure 33-38. Gain Error vs. V_{CC}

T = 25°C, V_{REF} = external 1.0V, ADC sample rate = 300ksps

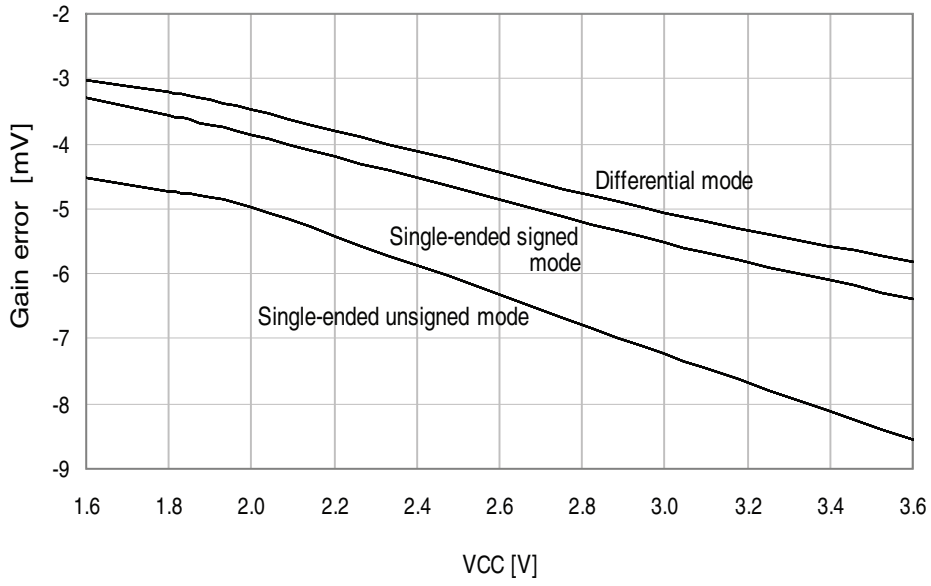
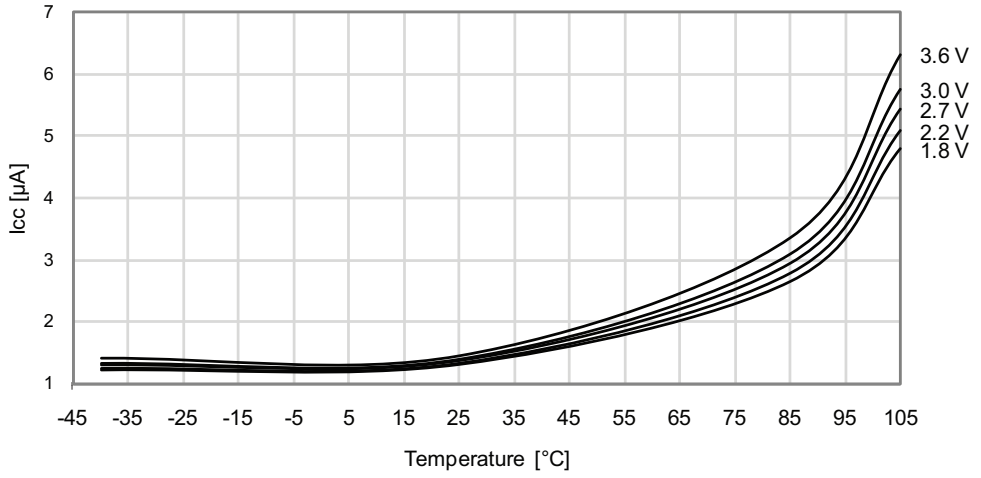


Figure 33-159. Power-down Mode Supply Current vs. Temperature

Watchdog and sampled BOD enabled and running from internal ULP oscillator



33.3.2 I/O Pin Characteristics

33.3.2.1 Pull-up

Figure 33-160. I/O Pin Pull-up Resistor Current vs. Input Voltage

V_{CC} = 1.8V

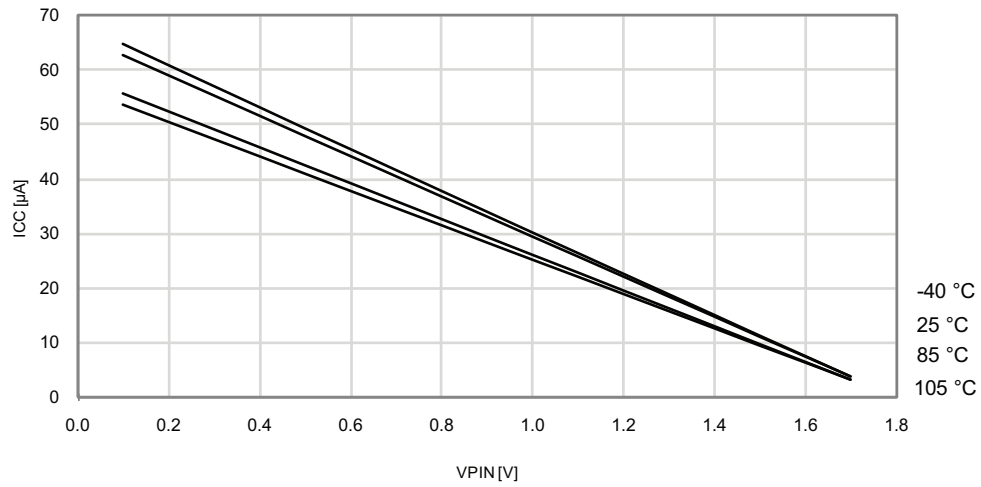


Figure 33-173. INL Error vs. Sample Rate

T = 25°C, V_{CC} = 3.6V, V_{REF} = 3.0V external

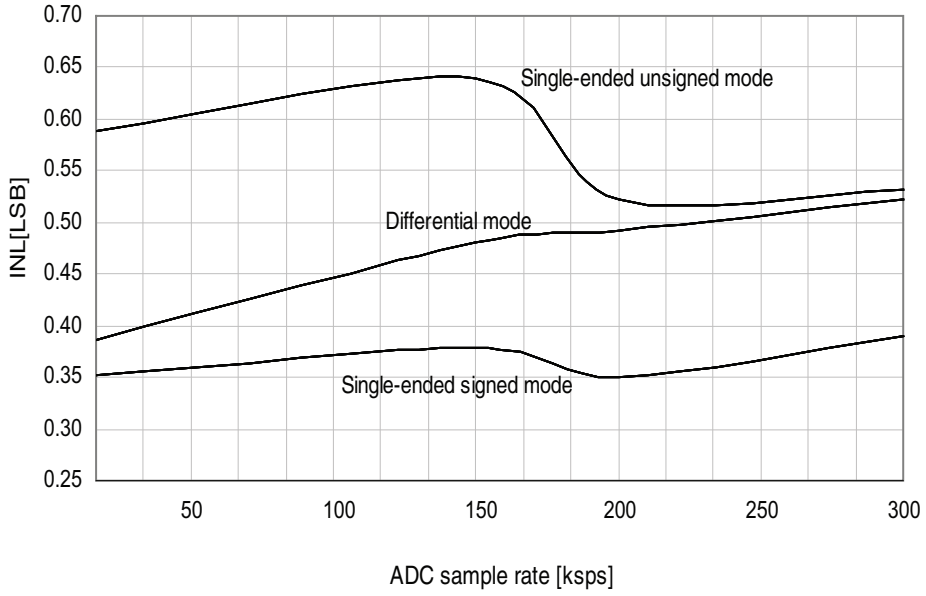


Figure 33-174. INL Error vs. Input Code

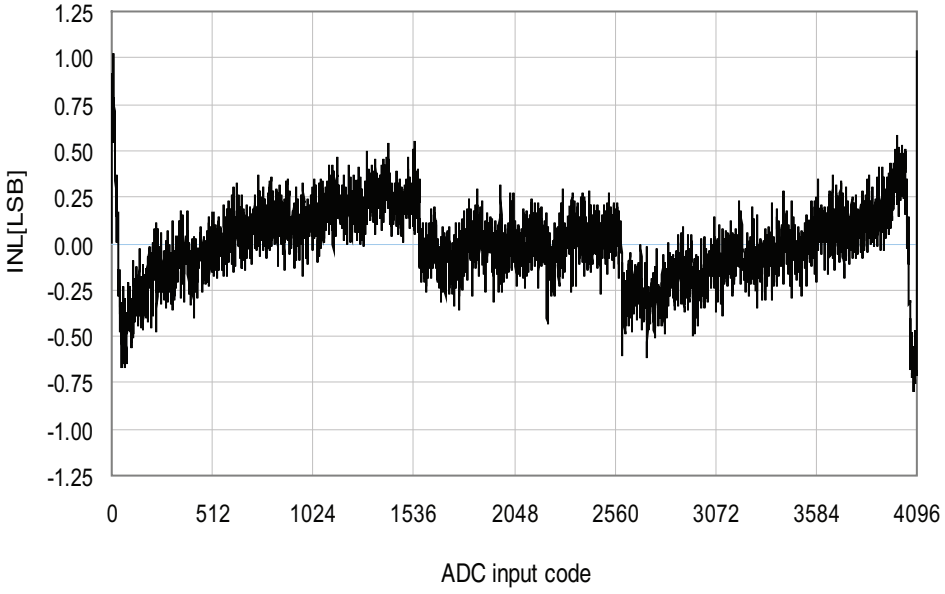


Figure 33-193. Reset Pin Pull-up Resistor Current vs. Reset Pin Voltage

V_{CC} = 3.3V

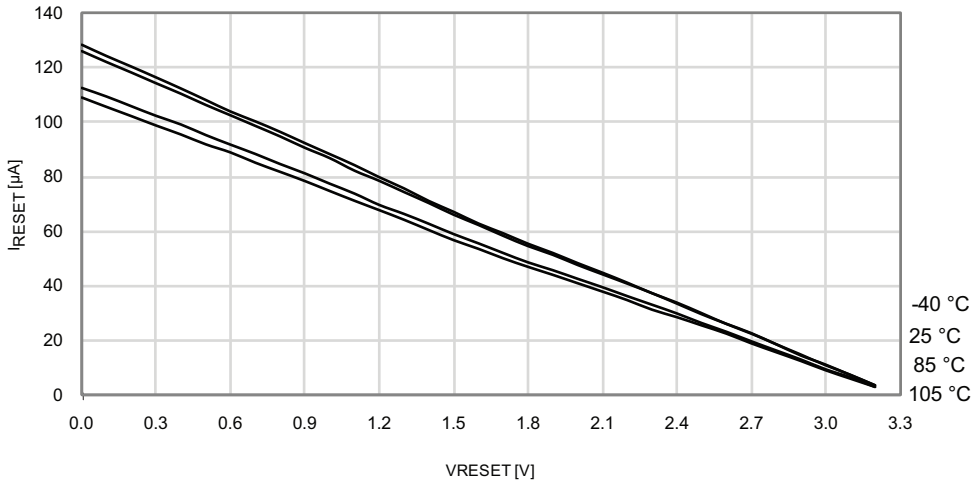


Figure 33-194. Reset Pin Input Threshold Voltage vs. V_{CC}

V_{IH} - Reset pin read as "1"

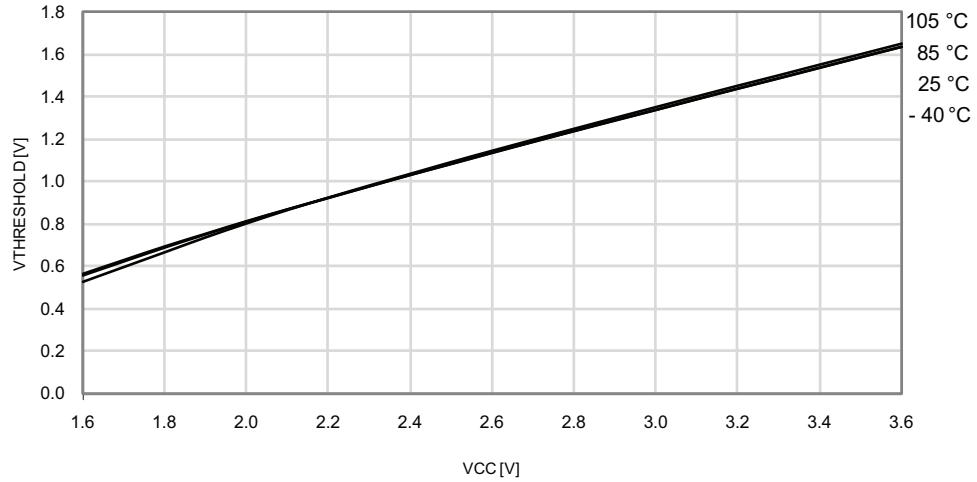
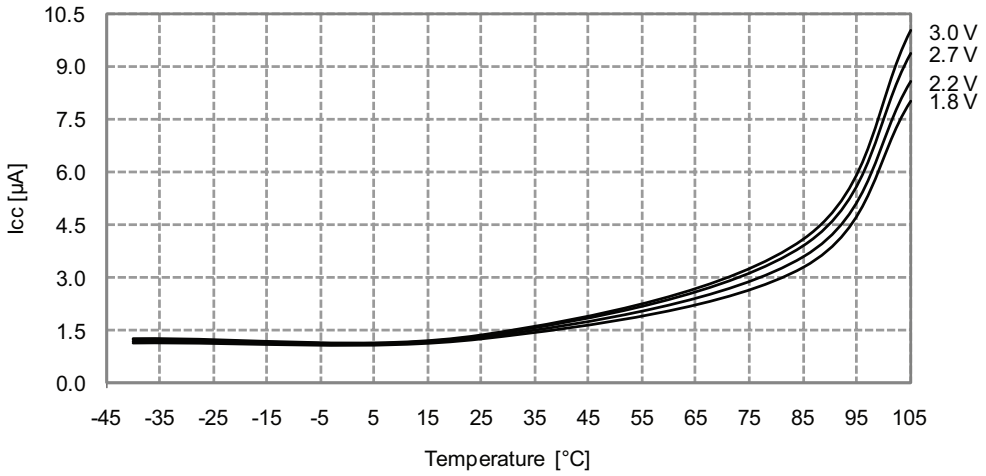


Figure 33-229.Power-down Mode Supply Current vs. Temperature

Watchdog and sampled BOD enabled and running from internal ULP oscillator



33.4.2 I/O Pin Characteristics

33.4.2.1 Pull-up

Figure 33-230.I/O Pin Pull-up Resistor Current vs. Input Voltage

V_{CC} = 1.8V

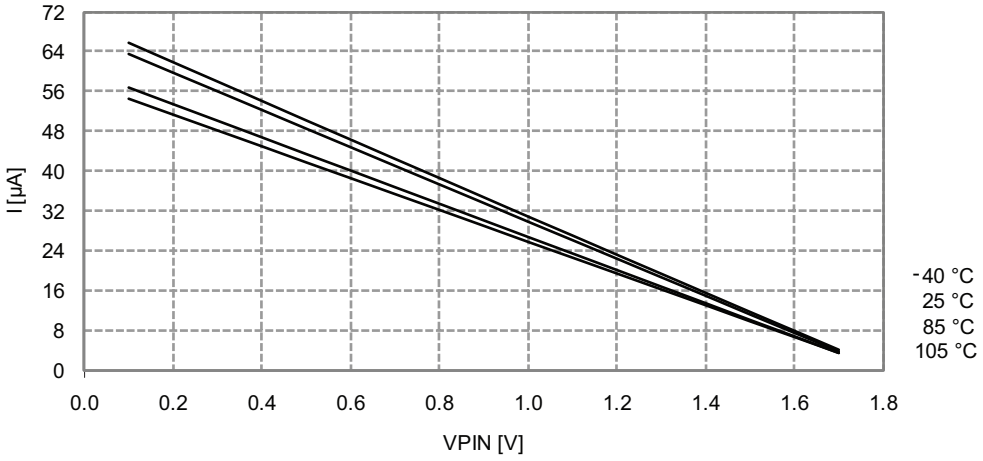


Figure 33-245.DNL Error vs. External V_{REF}

T = 25°C, V_{CC} = 3.6V, external reference

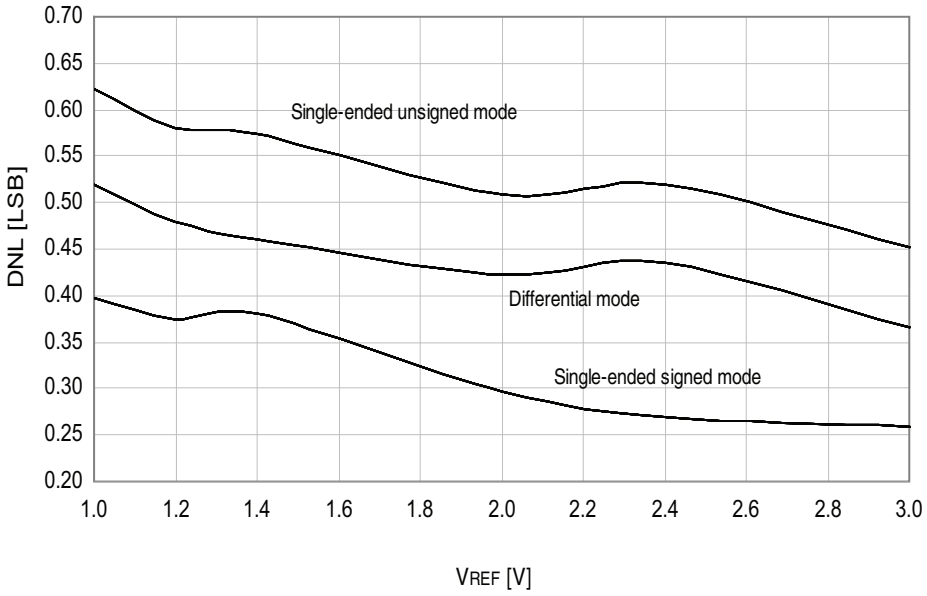
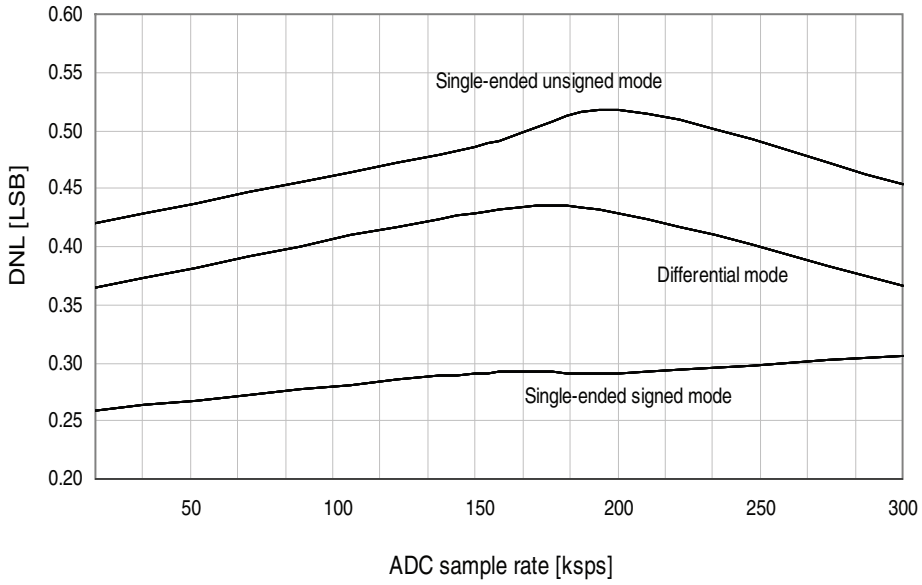


Figure 33-246.DNL Error vs. Sample Rate

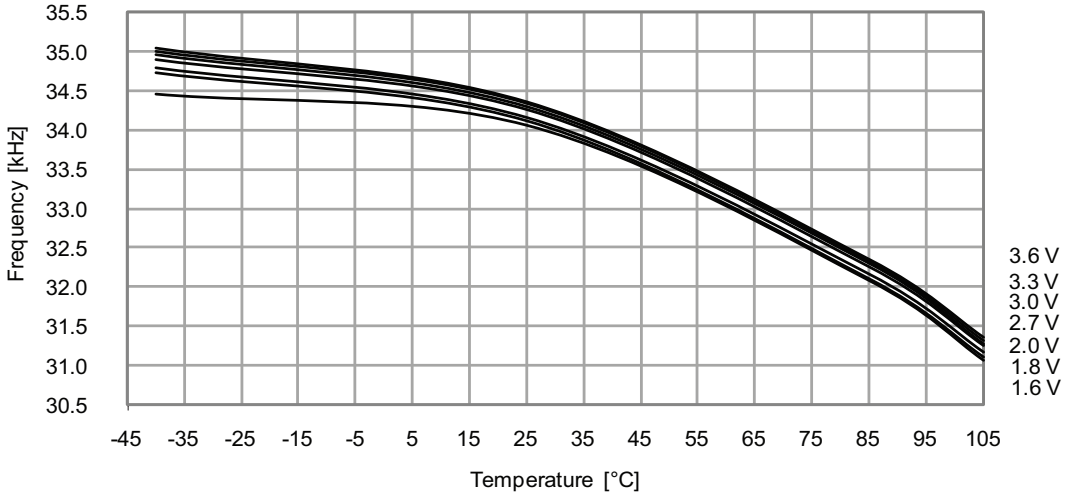
T = 25°C, V_{CC} = 3.6V, V_{REF} = 3.0V external



33.4.8 Oscillator Characteristics

33.4.8.1 Ultra Low-Power Internal Oscillator

Figure 33-265.Ultra Low-Power Internal Oscillator Frequency vs. Temperature



33.4.8.2 32.768kHz Internal Oscillator

Figure 33-266.32.768kHz Internal Oscillator Frequency vs. Temperature

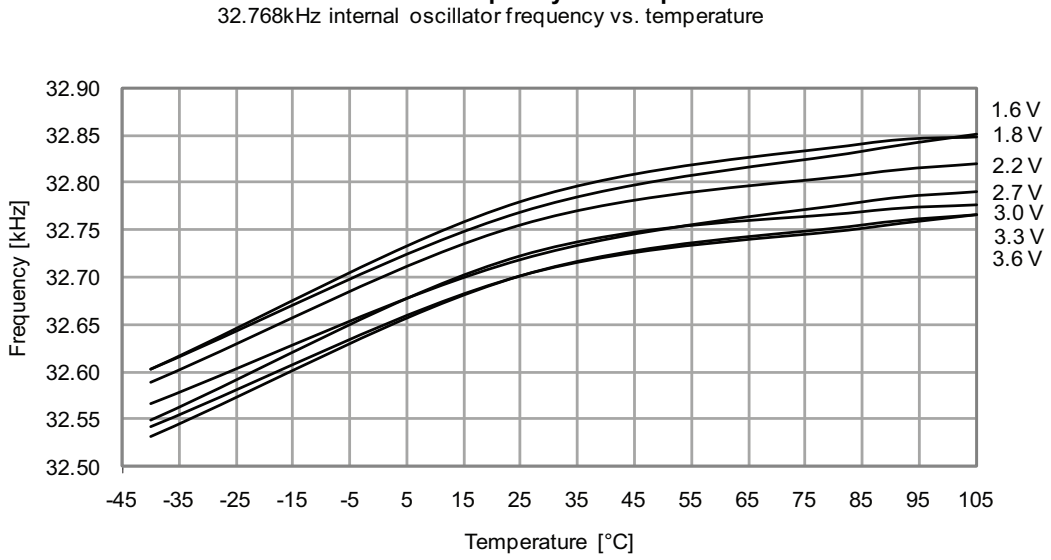


Figure 33-275. 32MHz Internal Oscillator CALA Calibration Step Size

T = 85°C, V_{CC} = 3.0V

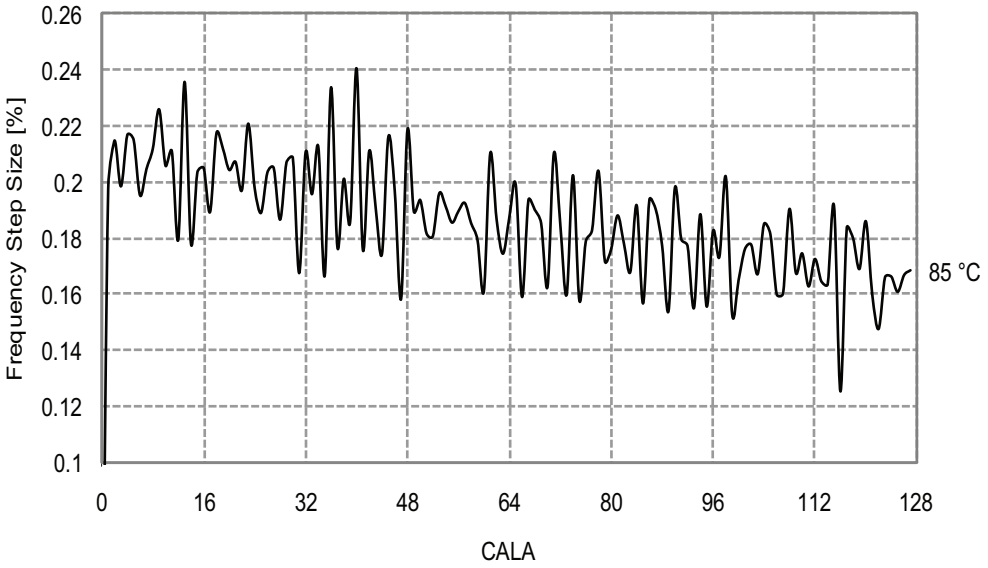


Figure 33-276. 32MHz Internal Oscillator CALA Calibration Step Size

T = 105°C, V_{CC} = 3.0V

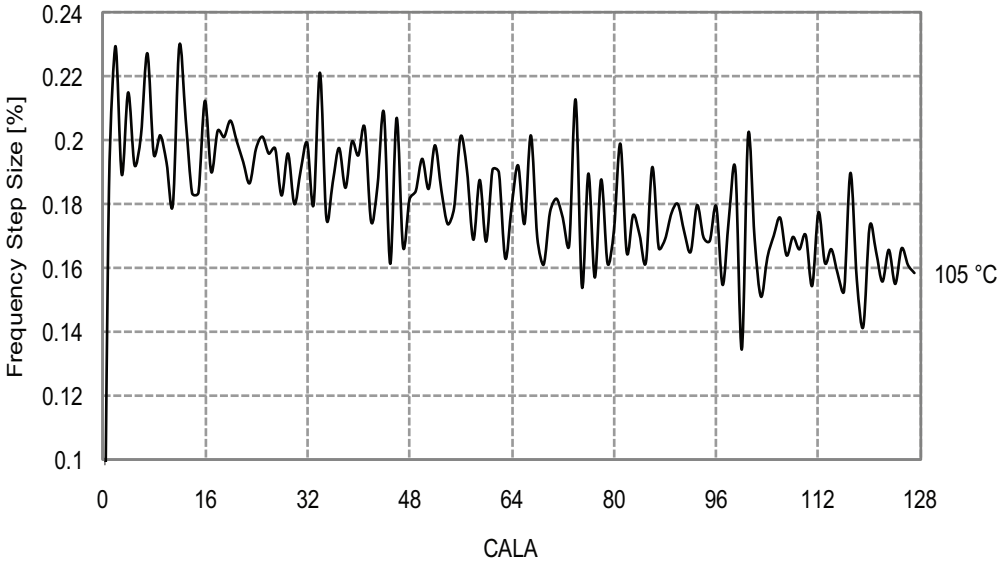


Figure 33-285.Active Mode Supply Current vs. V_{CC}

f_{SYS} = 32.768kHz internal oscillator

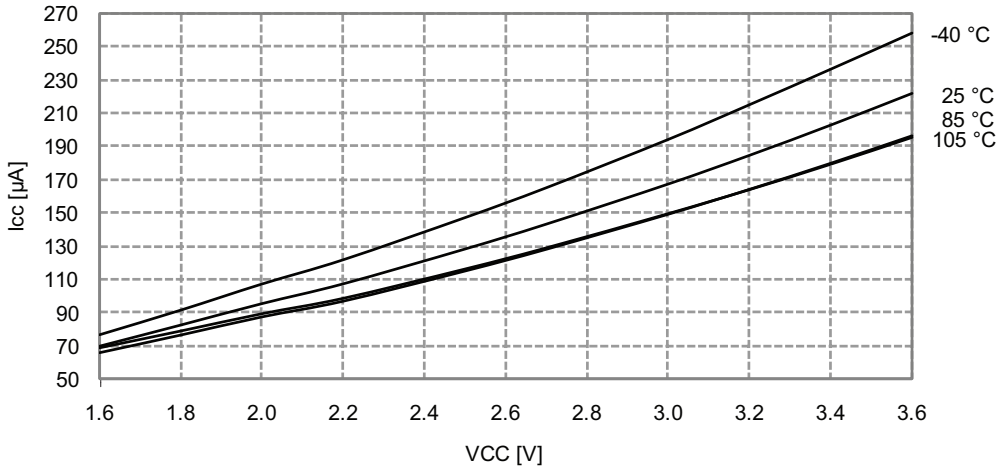
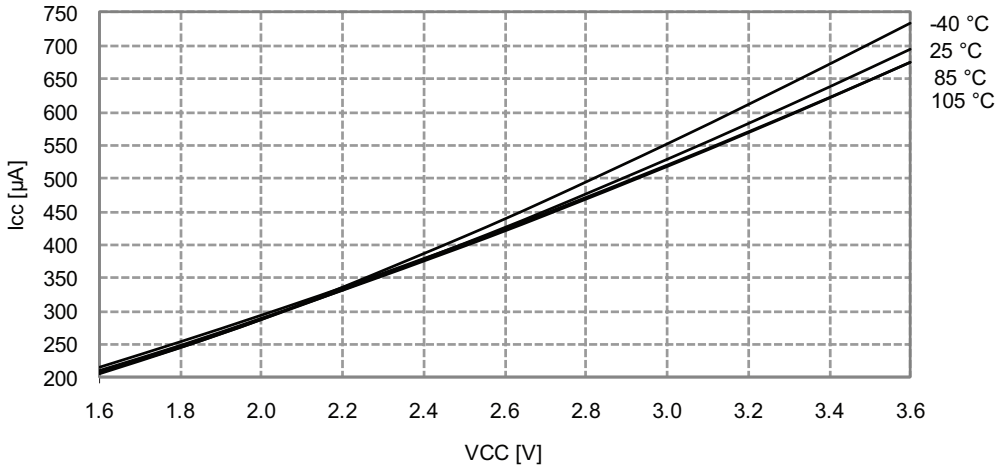


Figure 33-286.Active Mode Supply Current vs. V_{CC}

f_{SYS} = 1MHz external clock



33.6.1.3 Power-down Mode Supply Current

Figure 33-367.Power-down Mode Supply Current vs. V_{CC}

All functions disabled

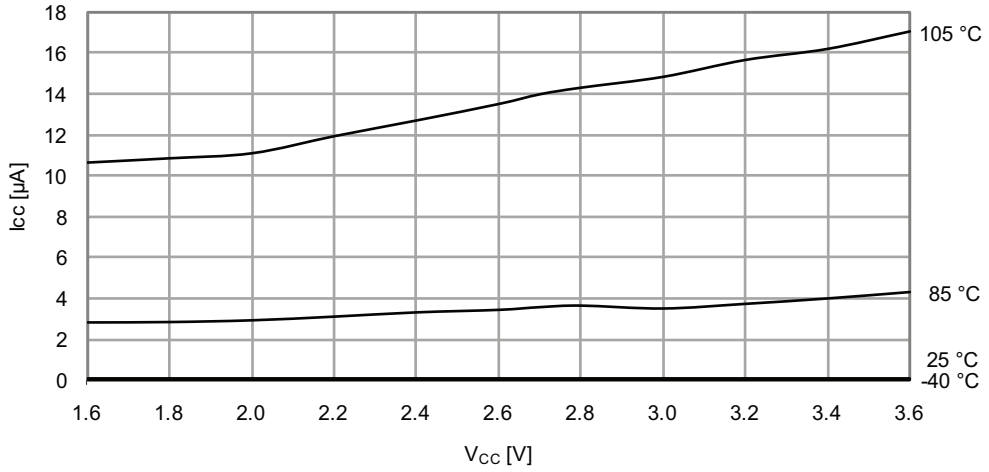


Figure 33-368.Power-down Mode Supply Current vs. V_{CC}

Watchdog and sampled BOD enabled

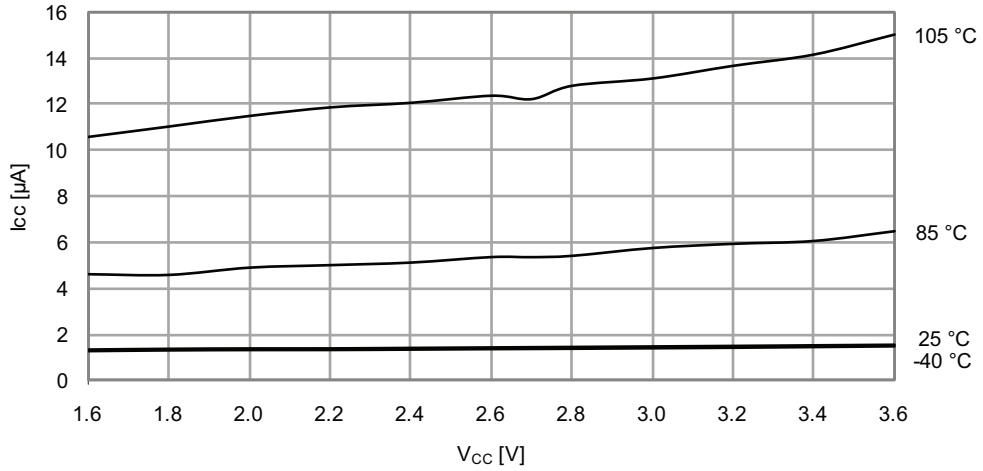
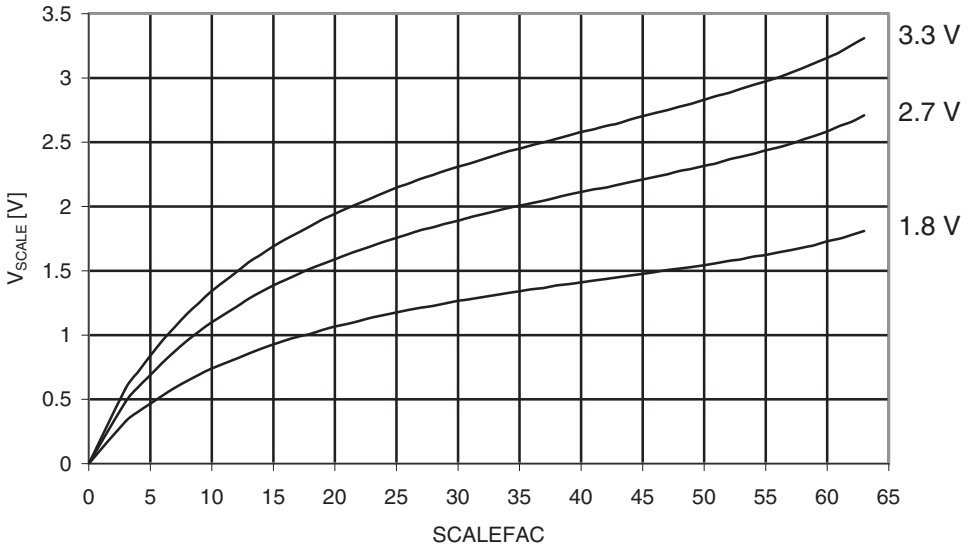


Figure 34-4. Analog Comparator Voltage Scaler vs. Scalefac
T = 25°C



Problem fix/workaround

Use external voltage input for the analog comparator if accurate voltage levels are needed.

3. ADC gain stage cannot be used for single conversion

The ADC gain stage will not output correct result for single conversion that is triggered and started from software or event system.

Problem fix/workaround

When the gain stage is used, the ADC must be set in free running mode for correct results.

4. ADC has increased INL error for some operating conditions

Some ADC configurations or operating condition will result in increased INL error.

In signed mode INL is increased to:

6LSB for sample rates above 130ksps, and up to 8LSB for 200ksps sample rate.

6LSB for reference voltage below 1.1V when V_{CC} is above 3.0V.

20LSB for ambient temperature below 0°C and reference voltage below 1.3V.

In unsigned mode, the INL error cannot be guaranteed, and this mode should not be used.

Problem fix/workaround

None, avoid using the ADC in the above configurations in order to prevent increased INL error. Use the ADC in signed mode also for single ended measurements.

5. ADC gain stage output range is limited to 2.4V

The amplified output of the ADC gain stage will never go above 2.4V, hence the differential input will only give correct output when below 2.4V/gain. For the available gain settings, this gives a differential input range of:

- CRC generator module
- ADC 1/2× gain option, and this configuration option in the GAIN bits in the ADC Channel CTRL register
- ADC VCC/2 reference option and this configuration option in the REFSEL bits on the ADC REFCTRL register
- ADC option to use internal Gnd as negative input in differential measurements and this configuration option in the MUXNEG bits in the ADC Channel MUXCTRL register
- ADC channel scan and the ADC SCAN register
- ADC current limitation option, and the CURRLIMIT bits in the ADC CTRLB register
- ADC impedance mode selection for the gain stage, and the IMPMODE bit in the ADC CTRLB register
- Timer/Counter 2 and the SPLITMODE configuration option in the BYTEM bits in the Timer/Counter 0 CTRLE register
- Analog Comparator (AC) current output option, and the AC CURRCTRL and CURRCALIB registers
- PORT remap functions with alternate pin locations for Timer/Counter output compare channels, USART0 and SPI, and the PORT REMAP register
- PORT RTC clock output option and the RTCOUT bit in the PORT CLKEVOUT register
- PORT remap functions with alternate pin locations for the clock and event output, and the CLKEVPIN bit in the PORT CLKEVOUT register
- TOSC alternate pin locations, and TOSCSEL bit in FUSEBYTE2
- Real Time Counter clock source options of external clock from TOSC1, and 32.768kHz from TOSC, and 32.768kHz from the 32.768kHz internal oscillator, and these configuration options in the RTCSRC bits in the Clock RTCTRL register
- PLL divide by two option, and the PLLDIV bit in the Clock PLLCTRL register
- PLL lock detection failure function and the PLLDIF and PLLFDEN bits in the Clock XOSCFAIL register
- The high drive option for external crystal and the XOSCPWR bit on the Oscillator XOSCCTRL register
- The option to enable sequential startup of the analog modules and the ANAINIT register in MCU Control memory

Problem fix/workaround

None.

27. Sampled BOD in Active mode will cause noise when bandgap is used as reference

Using the BOD in sampled mode when the device is running in Active or Idle mode will add noise on the bandgap reference for ADC, DAC and Analog Comparator.

Problem fix/workaround

If the bandgap is used as reference for either the ADC, DAC and Analog Comparator, the BOD must not be set in sampled mode.

28. Temperature sensor not calibrated

Temperature sensor factory calibration not implemented.

Problem fix/workaround

None.

28. Disabling of USART transmitter does not automatically set the TxD pin direction to input

If the USART transmitter is idle with no frames to transmit, setting TXEN to zero will not automatically set the TxD pin direction to input.